

Application/Control	No.
10/660.076	

Examiner

Kim T. Nguyen

Applicant(s)/Patent under Reexamination RANDALL ET AL.

Art Unit 3714

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(Assistant Examiner) (Date) Kim No. (Primary Examiner)					_		Z~ 2/1	4/07	Total Claims Allowed: 47 O.G. O.G Print Claim(s) Print F					
Lega Instruments Examiner) (Date)						ilei)		(Date)			8C & 8D			

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	19			49	1		79	1		109	1		139	1		169			199
	20			50			80	1		110	1		140]		170			200
	21			51			81			111	1		141	1		171]		201
	22			52	1		82	1		112	1		142	1		172			202
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	24	1		54	1		84	1		114			144	1		174	1		204
	25	1		55	1		85	1		115	1		145	1		175]		205
	26	1		56	1		86	1		116	1		146	1		176]		206
	27	1		57	1		87	1		117	1		147	1		177			207
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